## Notice of References Cited Application/Control No. 10/562,697 Examiner M. R. Sedighian Applicant(s)/Patent Under Reexamination HIETALA ET AL. Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-4,499,608	02-1985	Broockman et al.	398/164
	В	US-			
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	ם	US-			
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	F	US-			
	O	US-			
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	K	US-			
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	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	Ν	JP-2000-352634	12-2000	Japan	KIKUCHI HIDEO et al.	G02B 6/122
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## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.